

Application/Control No.	Applicant(s)/Patent under Reexamination
10/814,521	BOWEN, JOHN
Examiner	Art Unit
Chapman E. Jeanette	3635

		SEAR	CHED	
Cla	ass	Subclass	Date	Examiner
5	2	506.06, 506.08, 506.09	6/21/2005	JC
	1	506.03		
		506.04		
		474		
		762		
7	7	718.04	7	$\sqrt{}$
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INI	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner		

SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
Consulted with Slack for search in class 52	6/21/2005	JC		
see east text search				